REMARKS

At the outset, the Examiner is thanked for the thorough review and consideration of the pending application. The Office Action dated May 29, 2007 has been received and its contents carefully reviewed.

Claims 2, 3, 18, 20, and 21 are rejected by the Examiner. With this response, claims 2, 3 and 18 are amended. Claims 2, 3, 18, 20, and 21 remain pending in this application with claims 8-16 having been withdrawn from consideration.

In the Office Action, claims 2, 3, 18, 20, and 21 are rejected under 35 U.S.C. § 103(a) as being unpatentable over Akahira (US Patent 6,471,352) in view Ueno (JP 09-166783) further in view of Ben-Zur (US Published Application No. 2005/0179708). Applicants respectfully traverse the rejection of claims 2, 3, and 18, 20, and 21 and request reconsideration.

Claims 2 and 3 as amended to recite a method for forming an alignment layer having a combination of features including, for example, "wherein the shift distance of the alignment material dropping unit is smaller than a distance between the holes, such that the second dropping paths are disposed in a region at a separation distance from the first dropping paths between the first dropping paths, whereby the alignment materials in the first and second dropping paths spread after dropping to contact each other." Applicants submit that Akahira, Ueno, and Ben-Zur, analyzed singly or in any combination do not teach at least this combination of features. For example, the Examiner relies on Figures 6A-6D of Ben-Zur to disclose "the shift distance of the alignment material dropping unit is smaller than a distance between the holes", however, Applicant submits that even if the Examiner is correct, Ben-Zur does not disclose "the shift distance ... such that the second dropping paths are disposed in a region at a separation distance from the first dropping paths between the first dropping paths, whereby the alignment materials in the first and second dropping paths spread after dropping to contact each other."

Accordingly, Applicants submit that claims 2 and 3 are each allowable over Akahira, Ueno and Ben-Zur for at least for this reason.

Claims 18, 20 and 21 each recite a method of forming an alignment layer of a liquid crystal display device having a combination of features including, for example, "wherein dropping first alignment material includes positioning the alignment material dropping unit at a first side of the substrate, and wherein dropping the second alignment material includes shifting

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the alignment material dropping unit along a second side opposite the first side of the substrate by a predetermined distance, and wherein the predetermined distance is smaller than a distance between the plurality of holes, such that the second dropping paths are disposed in the region at a separation distance from the first dropping paths between the first dropping paths, whereby the alignment material in the first and second dropping paths spreading so that the alignment materials in the first and second dropping paths contacted each other." Applicants submit that Akahira, Ueno, and Ben-Zur, analyzed singly or in any combination do not teach at least the combination of features identified above for reasons similar to those given above for claim 2. Accordingly, Applicants submit that claims 18, 20, and 21 are each allowable over Akahira, Ueno and Ben-Zur for at least this reason.

Applicants believe that the above amendments and remarks place the application in condition for allowance and early, favorable action is respectfully solicited.

If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. § 1.136, and any additional fees required under 37 C.F.R. § 1.136 for any necessary extension of time, or any other fees required to complete the filing of this response, may be charged to Deposit Account No. 50-0911. Please credit any overpayment to deposit Account No. 50-0911. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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